Advance Information Integrated Driver and MOSFET

The NCP81391/A integrates a MOSFET driver, high-side MOSFET and low-side MOSFET into a single package. The driver and MOSFETs have been optimized for high-current DC-DC buck-boost power conversion applications. The NCP81391/A integrated solution greatly reduces package parasitics and board space compared to a discrete component solution.

Features

- Capable of Average Currents up to 25 A
- Capable of Peak Currents up to 65 A
- Over 97% Peak–Efficiency
- Compatible with 3.3 V and 5 V PWM Inputs, with Tri-State
- Zero Current Detection for Improving Light Load Efficiency
- Optional Thermal Shutdown Protection
 - NCP81391: With Thermal Shutdown
 - NCP81391A: No Thermal Shutdown
- Internal Bootstrap Diode
- Undervoltage Lockout
- This is a Pb–Free Device

Applications

- E-Cigarettes
- Unmanned Aerial Vehicles



Figure 1. Application Diagram (Buck-Boost)

This document contains information on a new product. Specifications and information herein are subject to change without notice.



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(Note: Microdot may be in either location)

PINOUT DIAGRAM



ORDERING INFORMATION

Device	Package	Shipping [†]
NCP81391MNTXG	QFN31	2500 / Tape &
NCP81391AMNTXG	(Pb-Free)	Reel

⁺For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.



Figure 2. Simplified Block Diagram

Pin No.	Symbol	Description
1	PHASE	Bootstrap Capacitor Return
2	PGND2	Power Ground
3	CGND	Signal Ground
4	EN	Enable. There is a pull-down resistor to CGND for the NCP81391. No pull-down resistor for NCP81391A.
5	PWM	PWM Control Input: PWM = High → HS FET is on, LS FET is off PWM = Mid → HS FET is off, LS FET is off PWM = Low, ZCD_EN# = High → HS FET is off, LS FET is on PWM = Low, ZCD_EN# = Low → HS FET is off, LS FET is off when zero current is detected
6	ZCD_EN#	Zero Current Detect Control. When this pin is at logic low, low-side FET will turn off when zero inductor current is detected (after a minimum blanking/de-bounce time). There is an internal pull-up resistor.
7	VCC	Control Power Supply Input
8	VCCD	Driver Power Supply Input
9	NC9	No Connect
10	BST	Bootstrap Supply Voltage. Connect a MLCC capacitor of at least 0.1 μ F from this pin to PHASE.
11	GH	High-Side MOSFET Gate Access. Leave floating.
12	NC12	No Connect
13	VIN13	Conversion Supply Power Input
14	VIN14	Conversion Supply Power Input
15	VIN15	Conversion Supply Power Input

Pin No.	Symbol	Description
16	VIN16	Conversion Supply Power Input
17	VIN17	Conversion Supply Power Input
18	VIN18	Conversion Supply Power Input
19	VIN19	Conversion Supply Power Input
20	PGND20	Power Ground
21	PGND21	Power Ground
22	PGND22	Power Ground
23	PGND23	Power Ground
24	VSWH24	Switch Node Output
25	VSWH25	Switch Node Output
26	VSWH26	Switch Node Output
27	VSWH27	Switch Node Output
28	GLF28	Low-Side MOSFET Gate Access. Pins 28, 29, 30 and 31 must be connected together on the PCB.
29	GLF29	Low-Side MOSFET Gate Access. Pins 28, 29, 30 and 31 must be connected together on the PCB.
30	GLD30	Low-Side Driver Gate Access. Pins 28, 29, 30 and 31 must be connected together on the PCB.
31	GLD31	Low-Side Driver Gate Access. Pins 28, 29, 30 and 31 must be connected together on the PCB.
32	PGND32	Power Ground Flag
33	VIN33	Conversion Supply Power Input Flag
34	GL34	Low Side MOSFET Gate Access. Do not connect to PCB. See Recommended PCB Footprint for details.

Table 1. PIN LIST AND DESCRIPTIONS

Table 2. ABSOLUTE MAXIMUM RATINGS (Electrical Information – all signals referenced to PGND unless noted otherwise)

Pin Name	VMIN	VMAX	Unit
VCC, VCCD (DC)	-0.3	13.2	V
VCC, VCCD (< 100 ns)	-	15	V
VIN	-0.3	30	V
BST (DC)	-0.3	35	V
BST (< 10 ns)	-0.3	40	V
BST to PH (DC)	-0.3	13.2	V
VSWH, PHASE (DC)	-0.3	30	V
VSWH, PHASE (< 10 ns)	-5	35	V
GH (DC)	-	V _{BST} + 0.3	V
GH wrt/ VSWH (DC)	-0.3	13.2	V
GH wrt/ VSWH (< 200 ns)	-2	-	V
GH wrt/ VSWH (< 100 ns)	-	15	V
GL (DC)	-0.3	V _{VCC} + 0.3	V
GL (< 200 ns)	-5	-	V
GL (< 100 ns)	-	15	V
EN, ZCD_EN#, PWM	-0.3	6.5	V

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

Table 3. THERMAL INFORMATION

Rating	Symbol	Value	Unit
Thermal Resistance (Note 1)	θ_{J-A}	23	°C/W
	$R\psi_{J-BT}$	0.3	°C/W
	$R\psi_{J-CT}$	0.5	°C/W
Operating Junction Temperature Range (Note 2)	ТJ	-40 to +150	°C
Operating Ambient Temperature Range	T _A	-40 to +125	°C
Maximum Storage Temperature Range	T _{STG}	-40 to +150	°C
Maximum Power Dissipation	PD	5.4	W
Moisture Sensitivity Level	MSL	3	

1. JESD 51-7 (2S2P Direct-Attach Method) with 0 LFM

2. The maximum package power dissipation must be observed.

Table 4. RECOMMENDED OPERATING CONDITIONS

Parameter	Pin Name	Conditions	Min	Тур	Мах	Unit
Supply Voltage Range	VCC, VCCD		4.5	12	13.2	V
Conversion Voltage	VIN		4.5	12	20	V
Continuous Output Current		F _{SW} = 250 kHz			25	А
Peak Output Current		F_{SW} = 250 kHz, V_{VIN} = 12 V, V_{OUT} = 6 V, Duration = 10 ms, Period = 1 s			65	A
Operating Temperature			-40		100	°C

Functional operation above the stresses listed in the Recommended Operating Ranges is not implied. Extended exposure to stresses beyond the Recommended Operating Ranges limits may affect device reliability.

Table 5. ELECTRICAL CHARACTERISTICS $(V_{VCC} = V_{VCCD} = 12 \text{ V}, V_{VIN} = 12 \text{ V}, V_{EN} = 5.0 \text{ V}, C_{VCCD} = C_{VCC} = 0.1 \mu \text{F}$ unless specified otherwise) Min/Max values are valid for the temperature range $-40^{\circ}\text{C} \le T_A \le 100^{\circ}\text{C}$ unless noted otherwise, and are guaranteed by test, design or statistical correlation.)

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
VCC						
Operating Current	I _{VCC_PWM}	EN = 5 V, PWM = 250 kHz	-	-	2	mA
Enabled, No switching	I _{VCC_EN}	EN# = 5 V, PWM = 0 V, ZCD_EN# = 5 V	-	-	2	mA
	Ivcc_zcd	EN# = 5 V, PWM = 0 V, ZCD_EN# = 0 V	Ι	-	2	mA
Disabled Current	I _{VCC_DIS}	EN = 0 V, ZCD_EN# = 5 V	Ι	960	1500	μΑ
	IVCC_DIS_ZCD	EN = 0 V, ZCD_EN# = 0 V	Ι	960	1500	μΑ
UVLO Threshold	V _{UVLO}	VCC rising	3.8	4.35	4.5	V
UVLO Hysteresis	V _{UVLO_HYS}		150	200	-	mV
VCCD SUPPLY CURRENT						
Operating	I _{VCCD_PWM}	EN = 5 V, PWM = 250 kHz	_	47	70	mA
Enabled, No switching	I _{VCCD_EN}	EN = 5 V, PWM = 0 V NCP81391	Ι	-	100	μΑ
		EN = 5 V, PWM = 0 V NCP81391A	Ι	-	100	μΑ
Disabled	I _{VCCD_DIS}	EN = 0 V	-	60	100	μΑ
PWM INPUT						
Input High Voltage	V _{PWM_HI}		2.6	-	_	V
Input Mid Voltage	V _{PWM_MID}		1.4	-	1.8	V
Input Low Voltage	V _{PWM_LO}		-	-	0.6	V
PWM Input Resistance	R _{PWM}		-	162	_	kΩ
PWM Input Bias Voltage	V _{PWM_BIAS}	PWM pin is floating	-	1.6	-	V

Table 5. ELECTRICAL CHARACTERISTICS $(V_{VCC} = V_{VCCD} = 12 V, V_{VIN} = 12 V, V_{EN} = 5.0 V, C_{VCCD} = C_{VCC} = 0.1 \mu F$ unless specified otherwise) Min/Max values are valid for thetemperature range $-40^{\circ}C \le T_A \le 100^{\circ}C$ unless noted otherwise, and are guaranteed by test, design or statistical correlation.)

High Stop Driver Promotion Procession Delay, PVM Falling Tproverage Delay, PVM Falling Tproverage Delay, Leading Edge TrocL GL failing @ 1 V to GH-JSWH raing @ 1 V 6 13 20 ns Propagation Delay, PVM Falling Edge TroLL GL failing @ 1 V to GH-JSWH raing @ 1 V 6 13 20 ns Fall Time, High-Side Gate to RNH GH raining, 10% to 90% - 10 - ns Entering PVM Mid-state Propagation TPVM_ENTER.H PVM = High-to-Mid to GH-VSWH failing - 13 25 ns Delay, High-to-Mid State Propagation TPVM_ENTER.H PVM = Mid-to-High to GH-VSWH failing - 13 25 ns Delay, Mid-state Propagation TPVM_ENT_R PVM = Mid-to-High to GH-VSWH failing - 13 2 ns Inserting PVM Mid-state Propagation Treve_M_ENT_R QH-VSWH failing @ 1 V to GL raing @ 1 V 5 16 21 ns Rise Time, Low-Side Gate tipRVL GL raing, 10% to 90% - 13 2 ns Fail Time, Low-Side Gate tipRVL	Parameter	Symbol	Conditions	Min	Тур	Max	Unit
High Stip: DRIVER Propagation Delay, PWM Failing TevmAPD_F PWM to GH-VSWH failing @ 90% - 18 24 Non-overlap Delay, Leading Edge TNOL_L GL failing @ 1 V to V GH SWH rsing @ 1 V 6 13 20 ns Fail Time, High-Side Gate topRVH GH failing @ 1 V to V GH SWH rsing @ 1 V - 3.5 - ns Fail Time, High-Side Gate topRVH GH failing @ 1 V to V GH sing PWM Mid-state Propagation - 10 - ns Delay, High-to-Mid GH state Propagation TPVM_ENTER	PWM INPUT					-	
The second se	Input Leakage	I _{PWM_LK}		_	-	5	μΑ
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	HIGH SIDE DRIVER						
(Note 3) M. C. C. GH - VSWH rising @ 1 V Image: Comparison of the comparison of t	Propagation Delay, PWM Falling	T _{PWM,PD_F}	PWM = Low to GH–VSWH falling @ 90%	-	18	24	
Rise Time, High-Side Gate t _{DOVH} GH rising, 10% to 90%. - 10 - ns Entering PWM Mid-state Propagation Delay, High-to-Mid T _{PWM_ENTER_H} PWM = High-to-Mid to GH-VSWH falling - 20 - ns Exiting PWM Mid-state Propagation Delay, Mid-to-High T _{PWM_ENTER_H} PWM = Mid-to-High to GH-VSWH rising - 13 25 ns LOW SIDE DRIVER Tromation T _{PWM_ENTER} PWM = High to GL falling @ 90% - 15 22 ns Non-overlap Delay, Trailing Edge (Note 3) To_L, T (GL rising @ 1 V to GL rising @ 1 V to GL rising 0 % to 10% - 16 21 ns File Time, Low-Side Gate tb_DRVL GL rising 0 % to 10% - 13 25 ns Exiting PWM Mid-state Propagation Delay, Mid-to-Low T _{PWM_ENTER_L} PWM = Low-to-Mid to GL rising @ 10% - 13 25 ns No-Channel Ligh-Side MOSFET On Resistance T _{PWM_ENTER_L} PWM = Mid-to-Low to GL rising @ 10% - 1.7 - mQ Low to-Mid VEN_LLS From VIN to VSWH pin - 1.7 - <td>Non–overlap Delay, Leading Edge (Note 3)</td> <td>T_{NOL_L}</td> <td></td> <td>6</td> <td>13</td> <td>20</td> <td>ns</td>	Non–overlap Delay, Leading Edge (Note 3)	T _{NOL_L}		6	13	20	ns
Entering PWM Mid-state Propagation TPWM_ENTER_H PWM_EXT_H PWM = High-to-Mid to GH-VSWH falling - 20 - ns Delay, Mid-to-High TPWM_EXT_H WW = Mid-to-High to GH-VSWH falling - 13 25 ns Delay, Mid-to-High TPWM_EXT_H WW = Mid-to-High to GH-VSWH rising - 13 25 ns LOW SIDE ORIVER Promagation Delay, Trailing Edge T_NOL_T GH-VSWH falling @ 90% - 15 22 ns Non-overlap Delay, Trailing Edge T_NOL_T GH-VSWH falling @ 90% - 13 - ns Fail Time, Low-Side Gate tronvL GL falling, 90% to 10% - 13 - ns Entering PWM Mid-state Propagation TpWM_EXTER_L PWM = Mid-to-Low to 90% - 13 - ns Failt Time, Low-Side Gate tronvL GL rising, 10% to 90% - 13 25 ns Delay, Mid-to-Low TpWM_EXT_L PWM = Mid-to-Low to GL rising @ 10% - 13 25 ns MOSPET N Comm_EXT_L	Fall Time, High–Side Gate	t _{fDRVH}	GH falling, 90% to 10%	-	3.5	-	ns
Delay, High-to-Mid Mathematical @ 90% Mathematical With a model of the second	Rise Time, High-Side Gate	t _{rDRVH}	GH rising, 10% to 90%	-	10	-	ns
Delay, Mid-to-High Max. Letter @ 10% Constraints Constraints <thconstraints< th=""> Constantast for the t</thconstraints<>	Entering PWM Mid-state Propagation Delay, High-to–Mid	T _{PWM_ENTER_H}		-	20	-	ns
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Exiting PWM Mid-state Propagation Delay, Mid-to-High	T _{PWM_EXIT_H}		-	13	25	ns
Non-overlap Delay, Trailing Edge TNOL_T (Note 3) GH-VSWH falling @ 1 V to GL rising @ 1 V 5 16 21 ns Fall Time, Low-Side Gate t _{DRVL} GL falling, 90% to 10% - 13 - ns Rise Time, Low-Side Gate t _{DRVL} GL falling, 90% to 10% - 2.8 - ns Bite Time, Low-Side Gate t _{DRVL} GL rising, 10% to 90% - 30 - ns Entering PWM Mid-state Propagation T _{PWM_ENTER_L} PWM = Low-to-Mid to GL falling @ 90% - 13 25 ns MosFET N-Channel High-Side MOSFET On Resistance Tow_M_EXT_L PWM = Mid-to-Low to GL rising @ 10% - 1.7 - mQ N-Channel Low-Side MOSFET On Resistance RON_LS From VIN to VSWH pin - 1.7 - mQ N-Channel Low-Side MOSFET On Resistance RON_LS From VSWH to PGND pin - 1.7 - mQ N-Channel Low-Side MOSFET ON RON_LS From VSWH to PGND pin - 1.7 - mQ N-Channel Low-Side MOSFET ON <td>LOW SIDE DRIVER</td> <td></td> <td></td> <td></td> <td></td> <td></td> <td></td>	LOW SIDE DRIVER						
$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$	Propagation Delay, PWM Rising	T _{PWM,PD_R}	PWM = High to GL falling @ 90%	-	15	22	ns
Rise Time, Low-Side Gate t_{CRVL} GL rising, 10% to 90%-2.8-nsEntering PWM Mid-state Propagation Delay, Juo-to-Mid $T_{PWM_ENTER_L}$ PWM = Low-to-Mid to GL falling @ 90%-30-nsExiting PWM Mid-state Propagation Delay, Mid-to-Low $T_{PWM_ENTER_L}$ PWM = Mid-to-Low to GL rising @ 10%-1325nsMOSFETN-Channel High-Side MOSFET On Resistance R_{ON_HS} From VIN to VSWH pin-1.7-mΩN-Channel Low-Side MOSFET On Resistance R_{ON_HS} From VSWH to PGND pin-1.7-mΩEN INPUTInput LeakageI EN_LK NCP8139ANCP8139-2.0- μA Upper Threshold V_{EN_HI} Ven_HI2.0-NVLower ThresholdVEN_LO0.8VVicoParitive Resistance (NCP81391 Only)REN Pull-down resistance to CGND-300-kΩEnable Delay TimeT_EN_ONEN rising @ V_EN_HI to GH-VSWH rising @ -300-kΩRDisable Delay TimeT_EN_OFFEN rising @ V_EN_Lo to GL falling @ 90%, -15400nsZERO CURRENT DETECTION ENABLEVV2CD_ENB_HI2.0VZCD_EN# HighV2CD_ENB_HI2.0VZZCD_EN# HighV2CD_ENB_HI2.0VVZCD_EN# HighV2CD_ENB_HI2.0VZZCD_E	Non–overlap Delay, Trailing Edge (Note 3)	T _{NOL_T}		5	16	21	ns
Entering PWM Mid-state Propagation Delay, Low-to-Mid $T_{PWM_ENTER_L}$ PWM = Low-to-Mid to GL falling @ 90% Image: Power of GL rising @ 10%-30-nsExiting PWM Mid-state Propagation Delay, Mid-to-Low $T_{PWM_EXT_L}$ PWM = Mid-to-Low to GL rising @ 10%-1325nsMOSFET N-Channel High-Side MOSFET On Resistance R_{ON_HS} From VIN to VSWH pin-2.0-mΩN-Channel Low-Side MOSFET On Resistance R_{ON_LS} From VIN to VSWH pin-1.7-mΩN-Channel Low-Side MOSFET On Resistance R_{ON_LS} From VSWH to PGND pin-1.7-mΩN-Channel Low-Side MOSFET On Resistance R_{ON_LS} From VSWH to PGND pin-1.7-mΩN-Channel Low-Side MOSFET On Resistance R_{ON_LS} From VSWH to PGND pin-1.7-mΩN-Channel Low-Side MOSFET On Resistance R_{ON_LS} NCP8139A-2.0- μA Input Leakage I_{EN_LK} NCP8139A-5.0- nA Upper Threshold V_{EN_LH} NCP8139A-4.0NNLower Threshold V_{EN_LH} VEN_LHI - VEN_LO-4.70-mVLower Threshold V_{EN_LHS} VEN_HI - VEN_LO-4.70-mVEn Input Resistance (NCP81391 Only) R_{EN} Pull-down resistance to CGND-3.00-kΩDisable Delay Time T_{EN_OFF EN faling @ V _{EN_LO} to GL f	Fall Time, Low–Side Gate	t _{fDRVL}	GL falling, 90% to 10%	-	13	_	ns
Delay, Low-to-Mid Image: Content of the section of the sectin of the section of the section of the section of the s	Rise Time, Low-Side Gate	t _{rDRVL}	GL rising, 10% to 90%	-	2.8	_	ns
Delay, Mid-to-Low Normalization Nor	Entering PWM Mid-state Propagation Delay, Low-to-Mid	T _{PWM_ENTER_L}	PWM = Low-to-Mid to GL falling @ 90%	-	30	-	ns
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Exiting PWM Mid-state Propagation Delay, Mid-to–Low	T _{PWM_EXIT_L}	PWM = Mid-to-Low to GL rising @ 10%	-	13	25	ns
ResistanceRomanResistanceRomanRom	MOSFET	•			4		·
Resistance NCE NCE NC NC NC EN INPUT Input Leakage I I NC I	N–Channel High–Side MOSFET On Resistance	R _{ON_HS}	From VIN to VSWH pin	-	2.0	-	mΩ
$\begin{array}{ c c c c c c c c c c c c c c c c c c c$	N–Channel Low–Side MOSFET On Resistance	R _{ON_LS}	From VSWH to PGND pin	-	1.7	-	mΩ
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	EN INPUT	•			4		·
Upper ThresholdVVNNNNLower ThresholdVEN_LOVLower ThresholdVEN_LO0.8VHysteresisVEN_HYSVEN_HI - VEN_LO-470-mVEN Input Resistance (NCP81391 Only)RENPull-down resistance to CGND-300-kΩEnable Delay TimeTEN_ONEN rising @ VEN_HI to GH-VSWH rising @ 10%, PVWH = High-30-nsDisable Delay TimeTEN_OFFEN falling @ VEN_LO to GL falling @ 90%, PWM = Low-1540nsZECD_EN# HighVZCD_ENB_HI2.0VZCD_EN# HighVZCD_ENB_HI2.0VZCD_EN# HighVZCD_ENB_HI0.8VHysteresisVZCD_ENB_HI0.8VHysteresisVZCD_ENB_HYS725-kQCD_EN# Input ResistanceRZCD_ENBPull-up resistance to internal 3.84 V-725-kQ	Input Leakage	I _{EN_LK}	NCP8139	-	20	-	μΑ
Lower Threshold V_{EN_LO} 0.8VHysteresis V_{EN_HYS} $VEN_HI - VEN_LO$ -470-mVEN Input Resistance (NCP81391 Only) R_{EN} Pull-down resistance to CGND-300-k Ω Enable Delay Time T_{EN_ON} EN rising @ V_{EN_HI} to GH-VSWH rising @ 10% , PWM = High-30-nsDisable Delay Time T_{EN_OFF} EN falling @ V_{EN_LO} to GL falling @ 90%, $PWM = Low$ -1540nsZERO CURRENT DETECTION ENABLEZCD_EN# High $V_{ZCD_ENB_HI}$ 2.0VZCD_EN# Low $V_{ZCD_ENB_HI}$ 0.8VHysteresis $V_{ZCD_ENB_HIS}$ 470-mVZCD_EN# Input Resistance R_{ZCD_ENB} Pull-up resistance to internal 3.84 V-725-k Ω			NCP8139A	-	50	_	nA
Hysteresis V_{EN_HYS} $VEN_HI - VEN_LO$ -470-mVEN Input Resistance (NCP81391 Only) R_{EN} Pull-down resistance to CGND-300-k Ω Enable Delay Time T_{EN_ON} EN rising @ V_{EN_HI} to GH-VSWH rising @ 10% , PWM = High-30-nsDisable Delay Time T_{EN_OFF} EN falling @ V_{EN_LO} to GL falling @ 90%, $PWM = Low$ -1540nsZERO CURRENT DETECTION ENABLEZCD_EN# High $V_{ZCD_ENB_HI}$ 2.0VZCD_EN# Low $V_{ZCD_ENB_HI}$ -0.8VHysteresis $V_{ZCD_ENB_HYS}$ -470-mVZCD_EN# Input Resistance R_{ZCD_ENB} Pull-up resistance to internal 3.84 V-725-k Ω	Upper Threshold	V _{EN_HI}		2.0	-	_	V
EN Input Resistance (NCP81391 Only) R_{EN} Pull-down resistance to CGND-300-k Ω Enable Delay Time T_{EN_ON} EN rising @ V_{EN_HI to GH-VSWH rising @ 10%, PWM = High-30-nsDisable Delay Time T_{EN_OFF} EN falling @ V_{EN_LO} to GL falling @ 90%, PWM = Low-1540nsZERO CURRENT DETECTION ENABLEZCD_EN# High $V_{ZCD_ENB_HI}$ 2.0VZCD_EN# High $V_{ZCD_ENB_HI}$ -0.8VHysteresis $V_{ZCD_ENB_HYS}$ -470-mVZCD_EN# Input Resistance R_{ZCD_ENB} Pull-up resistance to internal 3.84 V-725-k Ω	Lower Threshold	V _{EN_LO}		-	-	0.8	V
(NCP81391 Only)Ten_ONEN rising @ V _{EN_HI} to GH–VSWH rising @ 10%, PWM = High-30-nsDisable Delay TimeT _{EN_OFF} EN falling @ V _{EN_LO} to GL falling @ 90%, PWM = Low-1540nsZERO CURRENT DETECTION ENABLEZCD_EN# HighV _{ZCD_ENB_HI} 2.0VZCD_EN# HighV _{ZCD_ENB_HI} -0.8VHysteresisV _{ZCD_ENB_HYS} -470-mVZCD_EN# Input ResistanceR _{ZCD_ENB} Pull-up resistance to internal 3.84 V-725-kΩ	Hysteresis	V _{EN_HYS}	Ven_hi – Ven_lo	-	470	_	mV
Image: Disable Delay TimeT10%, PWM = HighImage: Disable Delay TimeTNNDisable Delay TimeTTEN falling @ VVN1540nsZERO CURRENT DETECTION ENABLEZCD_EN# HighVVVNVZCD_EN# HighVVVNNVZCD_EN# LowVVNVZCD_EN# LowVVN-0.8VHysteresisVVN-470-mVZCD_EN# Input ResistanceRRPull-up resistance to internal 3.84 V-725-kQ	EN Input Resistance (NCP81391 Only)	R _{EN}	Pull-down resistance to CGND	-	300	-	kΩ
PWM = Low PWM = Low Image: Comparison of the state	Enable Delay Time	T _{EN_ON}	EN rising @ V _{EN_HI} to GH–VSWH rising @ 10%, PWM = High	-	30	-	ns
ZCD_EN# HighV_ZCD_ENB_HI2.0VZCD_EN# LowVZCD_ENB_LO0.8VHysteresisVZCD_ENB_HYS-470-mVZCD_EN# Input ResistanceRZCD_ENBPull-up resistance to internal 3.84 V-725-kΩ	Disable Delay Time	T _{EN_OFF}		-	15	40	ns
ZCD_EN# LowVzcD_ENB_LO0.8VHysteresisVzcD_ENB_HYS-470-mVZCD_EN# Input ResistanceRzCD_ENBPull-up resistance to internal 3.84 V-725-kΩ	ZERO CURRENT DETECTION ENAB	BLE					
Hysteresis VzcD_ENB_HYS - 470 - mV ZCD_EN# Input Resistance RzcD_ENB Pull-up resistance to internal 3.84 V - 725 - kΩ	ZCD_EN# High	V _{ZCD_ENB_HI}		2.0	_	-	V
ZCD_EN# Input Resistance R _{ZCD_ENB} Pull-up resistance to internal 3.84 V - 725 - kΩ	ZCD_EN# Low	V _{ZCD_ENB_LO}		-	-	0.8	V
	Hysteresis	V _{ZCD_ENB_HYS}		_	470	-	mV
ZCD Threshold V _{ZCD_ENB_TH} ZCD_EN# = 0 V, PWM = 0 V - -3 - mV	ZCD_EN# Input Resistance	R _{ZCD_ENB}	Pull–up resistance to internal 3.84 V	_	725	_	kΩ
	ZCD Threshold	$V_{ZCD_ENB_TH}$	ZCD_EN# = 0 V, PWM = 0 V	_	-3	-	mV

Table 5. ELECTRICAL CHARACTERISTICS

 $(V_{VCC} = V_{VCCD} = 12 \text{ V}, V_{VIN} = 12 \text{ V}, V_{EN} = 5.0 \text{ V}, C_{VCCD} = C_{VCC} = 0.1 \mu\text{F}$ unless specified otherwise) Min/Max values are valid for the temperature range $-40^{\circ}\text{C} \le T_A \le 100^{\circ}\text{C}$ unless noted otherwise, and are guaranteed by test, design or statistical correlation.)

Parameter	Symbol	Conditions	Min	Тур	Max	Unit	
ZERO CURRENT DETECTION ENABLE							
ZCD Blanking + De-Bounce Timer	T _{BLANK}		-	130	_	ns	
THERMAL SHUTDOWN (For NCP81391 Only)							
Thermal Shutdown Temperature	T _{THDN}	Temperature at Driver Die	-	170	-	°C	
Thermal Shutdown Hysteresis	T _{THDN_HYS}		-	20	_	°C	
BOOSTSTRAP DIODE							
Forward Voltage	$V_{F_{BST}}$	Forward Bias Current = 2.0 mA	0.1	0.4	0.6	V	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

3. Guaranteed by design and/or characterization. This parameter is not tested in production.

TYPICAL CHARACTERISTICS



Figure 3. Efficiency – 12 V Input, 500 kHz



Figure 5. Efficiency – 12 V Input, 250 kHz



Figure 4. Power Loss – 12 V Input, 500 kHz



Figure 6. Power Loss – 12 V Input, 250 kHz





APPLICATIONS INFORMATION

Theory of Operation

Low-Side Driver

The low–side driver drives a ground–referenced low– $R_{DS(on)}$ N–Channel MOSFET. The voltage rail for the low–side driver is internally connected to VCCD and CGND.

The GLD pin connects directly to the output of the low-side driver. The GLF pins connects directly to the gate of the low-side MOSFET. See Figure 2. GLD and GLF are not connected inside the package. For proper operation, these pins must be connected together on the PCB.

High-Side Driver

The high–side driver drives a floating low– $R_{DS(on)}$ N–channel MOSFET. The gate voltage for the high–side driver is developed by a bootstrap circuit referenced to the PHASE pin, which is internally connected to the VSWH pin.

The bootstrap circuit is comprised of an internal diode and an external bootstrap capacitor. When the NCP81391/A is starting up, the VSWH pin is at ground, so the bootstrap capacitor charges up to VCCD through the bootstrap diode (see Figure 1). When the PWM input goes high, the high–side driver will begin to turn on the high–side MOSFET using the stored charge of the bootstrap capacitor. As the high–side MOSFET turns on, the voltage at the VSWH pin rises. When the high–side MOSFET is fully on, the VSWH voltage equals the VIN voltage, with the BST voltage higher than VIN by the amount of voltage on the bootstrap capacitor. The bootstrap capacitor is recharged when the switch node goes low during the next cycle.

Parasitic inductances and capacitances within the packaging and MOSFETs can cause significant ringing of the VSWH signal during turn–on and turn–off of the high–side MOSFET. When operating at high input voltages and high output currents, the peak ringing voltages on VSWH could cause the drain–to–source voltage across the MOSFETs to exceed its maximum rating. Including a resistor in series with the bootstrap capacitor can reduce the peak VSWH ringing voltages. A resistor value of 4 Ω is recommended when operating at VIN voltages greater than 16 V.

Overlap Protection Circuit

As PWM transitions between the logic high and logic low states, the driver circuitry prevents both MOSFETs from being on at the same time. While one MOSFET is turned off, the driver monitors the gate voltage of that MOSFET until it reaches 1 V. At this point, a non–overlap timer is started, and prevents the gate of the other MOSFET from going high until this timer expires. In the electrical characteristics table, this non–overlap timer is specified as the time between 1 V of the falling gate and 10% of the high value of the rising gate.

Three-State PWM Input

Switching PWM between logic-high and logic-low states allows the driver to operate in continuous conduction mode, as long as VCC is greater than the UVLO threshold and EN is high.

The PWM mid-state allows the NCP81391/A to enter a high-impedance mode, where both MOSFETs are off.

EN	PWM	ZCD_EN#	GH	GL			
LOW	Х	Х	LOW	LOW			
HIGH	LOW	HIGH	LOW	HIGH			
HIGH	MID	HIGH	LOW	LOW			
HIGH	HIGH	HIGH	HIGH	LOW			
HIGH	LOW	LOW	LOW	ZCD			
HIGH	MID	LOW	LOW	LOW			
HIGH	HIGH	LOW	HIGH	LOW			

Table 6. EN/PWM LOGIC TABLE

Zero Current Detection

At light load conditions, the inductor current can be negative due to the inductor current ripple. The zero current detection (ZCD) function in the NCP81391/A can prevent negative current during these light load conditions. When ZCD is active, the NCP81391/A will monitor the voltage at the VSWH pins when the LS FET is on and conducting. There is a blanking/de–bounce timer that delays when this monitoring starts, from the time GL goes high. As the inductor current falls towards zero, the voltage on VSWH will become less negative. When the VSWH voltage reaches the ZCD threshold, the LS FET is turned off. Positive current can still flow through the body diode of the LS FET, but the body diode will block any current in the negative direction.

ZCD is activated by placing ZCD_EN# in the logic-low state. There is an internal pull-up resistor at the ZCD_EN# pin.

Whenever VCC rises above the UVLO threshold, an auto-calibration is conducted on the ZCD Threshold. During the auto-calibration, the driver outputs will remain low and not respond to the PWM input. The auto-calibration cycle takes 28 µs to complete, typically.

Thermal Shutdown

With the NCP81391, if the driver temperature exceeds T_{THDN} , the part will enter thermal shutdown and turn off both MOSFETs. After the temperature decreases to T_{THDN} – T_{THDN} HYS, the part will resume normal operation.

For applications that prefer not to have this power stage have a thermal shutdown, the NCP81391A removes the thermal shutdown protection feature.

To distinguish between the NCP81391 and NCP81391A, externally, the NCP81391 has an internal pull-down resistor at the EN pin while the NCP81391A does not have an internal pull-down resistor at the EN pin.

Power Supply Decoupling

The NCP81391/A sources relatively large currents into the MOSFET gates. In order to maintain a constant and stable input supply voltage, low–ESR capacitors should be placed between VCC and GND and between VCCD and ground, close to the NCP81391/A. A 1 μ F to 4.7 μ F multilayer ceramic capacitor (MLCC) is sufficient. To further filter noise from VCCD from entering the VCC pin, placing a 10 Ω resistor between the VCC and VCCD pins is recommended.

Bootstrap Circuit

The bootstrap circuit uses an external charge storage capacitor (C_{BST}) and the internal bootstrap diode. The bootstrap capacitor should have a voltage rating twice the maximum VCCD supply voltage. A bootstrap capacitance of at least 100 nF with a minimum 25 V rating is recommended. For best performances, use a 1 μ F ceramic capacitor.

In order to prevent the bootstrap capacitor from discharging during conditions where the high side is turned on for a long time, such as high duty cycle or ZCD, a maximum duty cycle must be respected. The maximum duty cycle depends on the two time constants that appear during the charging time (converter's t_{off}) and discharging time (converter's t_{on}). To keep the bootstrap capacitor charged, the following relation must kept.

$$D \cdot \frac{Rdrv}{(1-D) \cdot Rbst} > 50$$

Thus, Dmax can be expressed as

$$Dmax = 1 - \frac{Rbst}{\frac{Rdrv}{50} + Rbst}$$

With the converter's duty cycle, R_{drv} the High–Side Driver equivalent resistance from VBST to VSWH (typically 5 k Ω), R_{bst} the bootstrap series resistor. Note that the bootstrap capacitance has no effect on maximum duty cycle since it is common in both time constants.

Example:

 $f_{sw} = 250 \text{ kHz}, \text{ R}_{drv} = 5 \text{ k}\Omega, \text{ R}_{bst} = 4 \Omega$, the maximum duty cycle allowed to keep the bootstrap capacitor charged is $D_{max} = 96\%$ and $t_{on_max} = D_{max}/f_{sw} = 3.84 \text{ }\mu\text{s}.$









Figure 11. Recommended Layout (Buck-Side)

PACKAGE DIMENSIONS



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